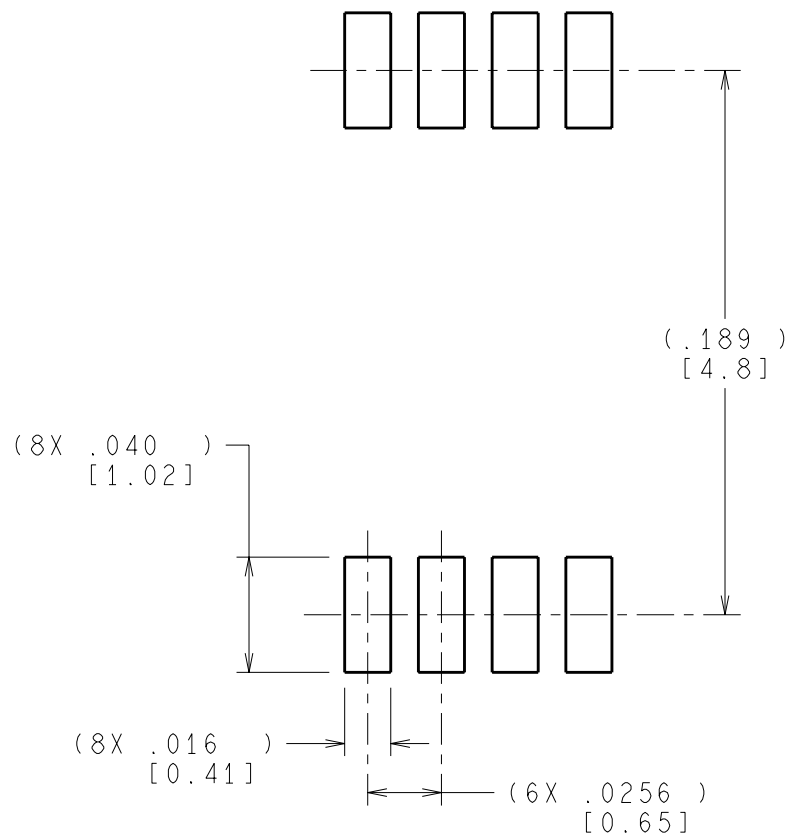
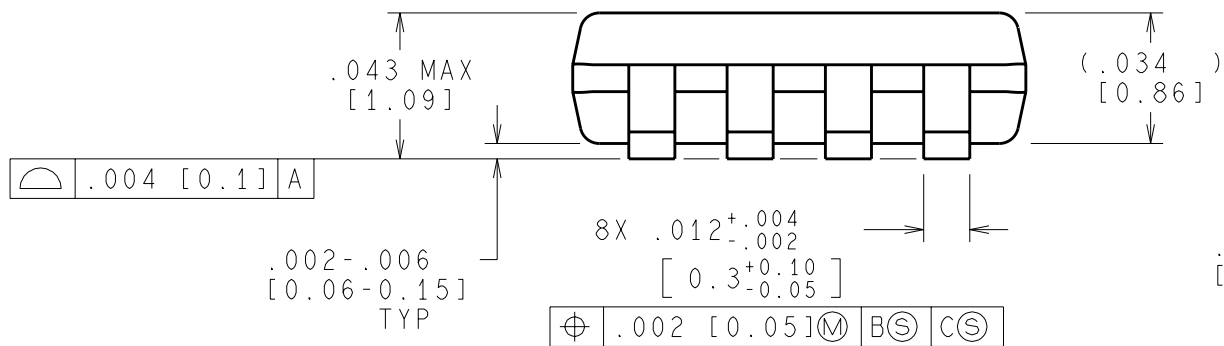
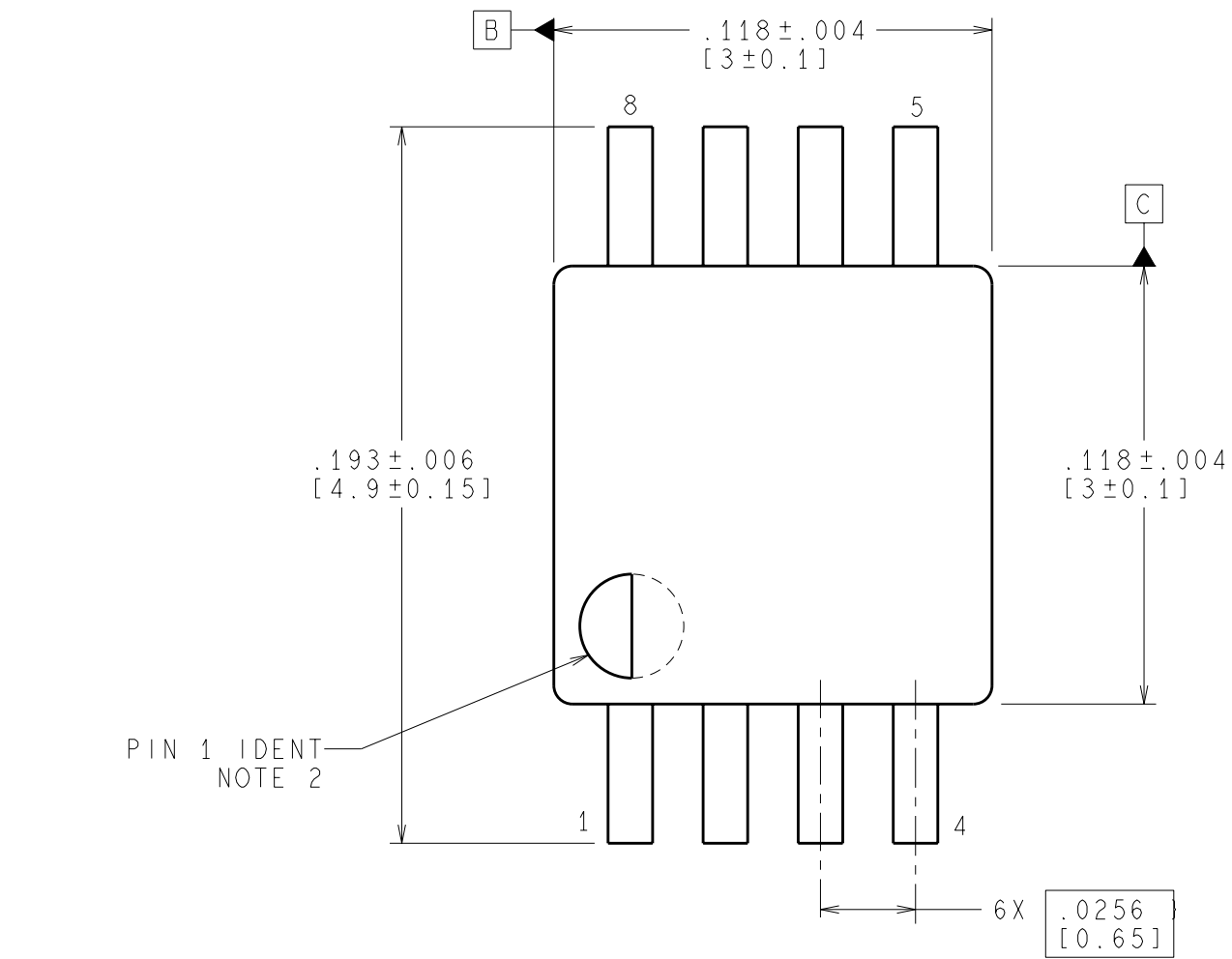
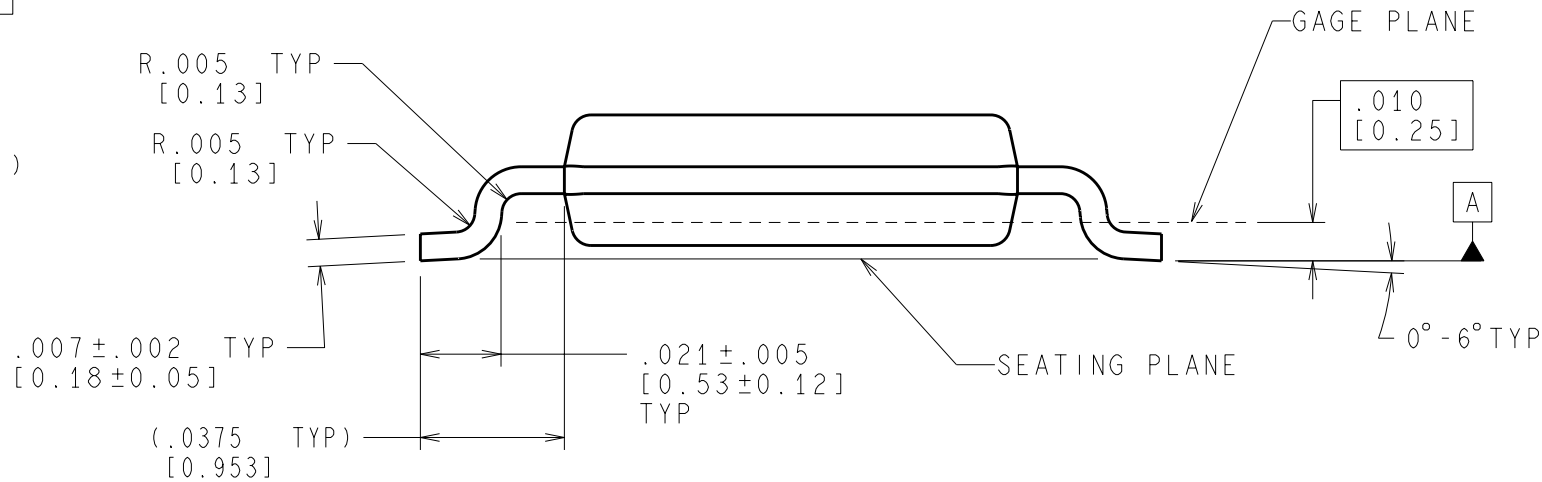


REVISIONS				
REV	DESCRIPTION	E.C.N.	DATE	BY/APP'D
A	RELEASE TO DOCUMENT CONTROL	11620	11/18/1996	TL/FL
B	DIM .043 MAX WAS .030-.037; DIM (.034) WAS (.033); DIM .193±.006 WAS .193±.004	11634	01/07/1997	MS/FL
C	COPLANARITY .004[0.1] WAS .002[0.05]; NOTE 1: 200 WAS 150; 5.08 WAS 3.81	11932	02/24/1998	MS/CD
D	DIM .043 MAX WAS .034	12170	03/12/1999	MS/CD
E	UPDATE DWG TO CURRENT STD'S; REVISE NOTE 1; UPDATE TITLE & NOTE 2; CHANGE TO B SIZE FORMAT.	1015	04/29/2003	MS/RW



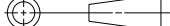
LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

1. FOR LEAD FINISH THICKNESS AND COMPOSITION, SEE "SOLDER INFORMATION" IN THE PACKAGING SECTION OF THE NATIONAL SEMICONDUCTOR WEB PAGE (www.national.com).
2. PIN 1 IDENTIFICATION TO HAVE HALF OR FULL CIRCLE OPTION.
3. REFERENCE JEDEC REGISTRATION MO-187, VARIATION AA.

CONTROLLING DIMENSION IS INCH
VALUES IN [] ARE MILLIMETERS

APPROVALS		DATE		 National Semiconductor 2900 Semiconductor Dr., Santa Clara, CA 95052-8090
DRAWN	THANH LEQUANG	11/18/1996		
DTFG, CHK.	THANH LEQUANG	04/29/2003		
ENGR, CHK.	RANDALL WALBERG	04/29/2003		
PROJECTION				MOLDED MINI-SO, .118x.118x.034in BODY, 8 LD, .0256in PITCH
				
INCH (MM)				
SCALE				
NTS				
SIZE		DRAWING NUMBER		REV
B		(SC)MKT-MUA08A		E
FORMERLY: N/A				SHEET 1 of 1